

<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)				ATTY DOCKET NO. 1TL1026US (P16713)		SERIAL NO. 10/688,521	
				APPLICANT(S): Robert P. Meagley et al.			
FILING DATE: October 17, 2005				GROUP ART UNIT: 1752			
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
JAN	A.	6,162,592	12/19/2000	Taylor et al.			
	B.						
	C.						
	D.						
	E.						
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>							
	F.						
	G.						
	H.						
	I.						
	J.						
<b>FOREIGN PATENT DOCUMENTS</b>							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
	K.						
	L.						
	M.						
	N.						
	O.						
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
JAN	P.	Lin et al., <i>Line Edge Roughness in Positive-Tone Chemically Amplified Resists: Effect of Additives and Processing Conditions</i> , Proceedings of the SPIE - The International Society for Optical Engineering, Vol. 4345, No. 1, Feb. 2001, pgs. 78-86.					
	Q.						
	R.						
	S.						
	T.						
U.							
EXAMINER Andrew C. Wacker				DATE CONSIDERED January 18, 2006			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.